## **MICROSCOPY TODAY**

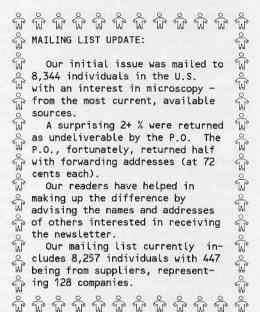
Greetings - - -

And thanks to the hundreds of our readers who have provided the names and addresses of their associates who are interested in receiving this newsletter. And a special thanks to the many of you who have contacted us with encouragement.

As the name selected for this newsletter might suggest, we are interested in the broad scope of microscopy. We ask all readers to pass their copy of the newsletter to others in their organizations who hold varying interests in the broad field. We are delighted to learn of others who would like a no cost subscription - by FAX (608-836-1969), by telephone (608-836-1970) or by mail.

Our plans include the development of an extensive data base of manufacturers and suppliers to the broad microscopy field and then to provide an equipment/services "locator" function, at no cost, to our readers. Should readers appreciate this "friendly" service, you are requested to advise manufacturers/suppliers that might call on you of our efforts. More on this subject on Page 2.

- - The Editors



## industry news

Our greatest challenge remains in obtaining "news" of interest. Please HELP!

\*\*\*\*\*\*\* CORRECTION: The correct telephone number for the toll free EMSA bulletin board is (800)627-3672

o The National Institute of Standards and Technology (NIST) has issued a new, comprehensive guide to its many research opportunities, facilities and services available to. industry. The guide summarizes major research programs that are potential bases for cooperative research and development agreements, describes the major specialized research facilities and lists all available services. Detailed descriptions, project managers and phone numbers are given for each item. Copies of "Research, Services, Facilities" can be obtained by sending a self addressed mailing label to NIST Public Affairs Division, A903 Administration Bldg., Gaithersburg MD 20899.

Z-contrast imaging represents a fundamentally new approach to high resolution electron microscopy. A focused probe in a scanning TEM ★★★★★★★★★★★★★★★★★★★★★★★ scans a sample and an annular detector collects electrons scattered through large angles. The scattered intensity is proportional to atomic number (Z) squared, so that a sufficiently fine probe maps out the location and scattering power of the materials atomic columns. An incoherent image results, showing characteristics similar to the image seen through a camera, but at atomic resolution. The most important aspect of Z-contrast imaging is the direct correspondence between object and image. For the first time, it is possible to determine the structure directly from the image with no need for any preconceived ideas or likely model structures. New interface structures are being observed leading to new insight into the atomic origin of material properties

and the atomistic mechanisms which occur during growth. The instrument is available from VG Microscopes

- PITTCON '50 boasted 14 exhibitors in 25 booths and around 800 visitors. PITTCON '90 in New York City had some 34,000 visitors and, this year in New Orleans, almost 1,000 exhibitors will display in nearly 3,000 booths.
- Tony Abbis, after management, marketing and sales positions with ARL and Hewlett Packard, has joined TopoMetrix as Senior V.P., Worldwide Marketing and Sales.

ggggggggggg YET ANOTHER ROSE - - -Link Analytical, Inc. & Ltd., is now Oxford Instruments, Microanalysis Division. aaaaaaaaaaaa